

* * * * * Welcome to STN International * * * * *

| | | |
|---------------------|--------|---|
| <u>NEWS 1</u> | | Web Page URLs for STN Seminar Schedule - N. America |
| <u>NEWS 2</u> | | "Ask CAS" for self-help around the clock |
| <u>NEWS 3</u> | Feb 24 | PCTGEN now available on STN |
| <u>NEWS 4</u> | Feb 24 | TEMA now available on STN |
| <u>NEWS 5</u> | Feb 26 | NTIS now allows simultaneous left and right truncation |
| <u>NEWS 6</u> | Feb 26 | PCTFULL now contains images |
| <u>NEWS 7</u> | Mar 04 | SDI PACKAGE for monthly delivery of multifile SDI results |
| <u>NEWS 8</u> | Mar 24 | PATDPAFULL now available on STN |
| <u>NEWS 9</u> | Mar 24 | Additional information for trade-named substances without structures available in REGISTRY |
| <u>NEWS 10</u> | Apr 11 | Display formats in DGENE enhanced |
| <u>NEWS 11</u> | Apr 14 | MEDLINE Reload |
| <u>NEWS 12</u> | Apr 17 | Polymer searching in REGISTRY enhanced |
| <u>NEWS 13</u> | SEP 09 | CA/CAPLUS records now contain indexing from 1907 to the present |
| <u>NEWS 14</u> | Apr 21 | New current-awareness alert (SDI) frequency in WPIDS/WPINDEX/WPIX |
| <u>NEWS 15</u> | Apr 28 | RDISCLOSURE now available on STN |
| <u>NEWS 16</u> | May 05 | Pharmacokinetic information and systematic chemical names added to PHAR |
| <u>NEWS 17</u> | May 15 | MEDLINE file segment of TOXCENTER reloaded |
| <u>NEWS 18</u> | May 15 | Supporter information for ENCOMPAT and ENCOMPLIT updated |
| <u>NEWS 19</u> | May 19 | Simultaneous left and right truncation added to WSCA |
| <u>NEWS 20</u> | May 19 | RAPRA enhanced with new search field, simultaneous left and right truncation |
| <u>NEWS 21</u> | Jun 06 | Simultaneous left and right truncation added to CBNB |
| <u>NEWS 22</u> | Jun 06 | PASCAL enhanced with additional data |
| <u>NEWS 23</u> | Jun 20 | 2003 edition of the FSTA Thesaurus is now available |
| <u>NEWS 24</u> | Jun 25 | HSDB has been reloaded |
| <u>NEWS 25</u> | Jul 16 | Data from 1960-1976 added to RDISCLOSURE |
| <u>NEWS 26</u> | Jul 21 | Identification of STN records implemented |
| <u>NEWS 27</u> | Jul 21 | Polymer class term count added to REGISTRY |
| <u>NEWS 28</u> | Jul 22 | INPADOC: Basic index (/BI) enhanced; Simultaneous Left and Right Truncation available |
| <u>NEWS 29</u> | AUG 05 | New pricing for EUROPATFULL and PCTFULL effective August 1, 2003 |
| <u>NEWS 30</u> | AUG 13 | Field Availability (/FA) field enhanced in BEILSTEIN |
| <u>NEWS 31</u> | AUG 15 | PATDPAFULL: one FREE connect hour, per account, in September 2003 |
| <u>NEWS 32</u> | AUG 15 | PCTGEN: one FREE connect hour, per account, in September 2003 |
| <u>NEWS 33</u> | AUG 15 | RDISCLOSURE: one FREE connect hour, per account, in September 2003 |
| <u>NEWS 34</u> | AUG 15 | TEMA: one FREE connect hour, per account, in September 2003 |
| <u>NEWS 35</u> | AUG 18 | Data available for download as a PDF in RDISCLOSURE |
| <u>NEWS 36</u> | AUG 18 | Simultaneous left and right truncation added to PASCAL |
| <u>NEWS 37</u> | AUG 18 | FROSTI and KOSMET enhanced with Simultaneous Left and Right Truncation |
| <u>NEWS 38</u> | AUG 18 | Simultaneous left and right truncation added to ANABSTR |
| <u>NEWS EXPRESS</u> | | April 4 CURRENT WINDOWS VERSION IS V6.01a, CURRENT MACINTOSH VERSION IS V6.0b(ENG) AND V6.0Jb(JP), AND CURRENT DISCOVER FILE IS DATED 01 APRIL 2003 |
| <u>NEWS HOURS</u> | | STN Operating Hours Plus Help Desk Availability |
| <u>NEWS INTER</u> | | General Internet Information |
| <u>NEWS LOGIN</u> | | Welcome Banner and News Items |
| <u>NEWS PHONE</u> | | Direct Dial and Telecommunication Network Access to STN |
| <u>NEWS WWW</u> | | CAS World Wide Web Site (general information) |

Enter NEWS followed by the item number or name to see news on that specific topic.

All use of STN is subject to the provisions of the STN Customer agreement. Please note that this agreement limits use to scientific research. Use for software development or design or implementation of commercial gateways or other similar uses is prohibited and may result in loss of user privileges and other penalties.

* * * * * STN Columbus * * * * *

FILE 'HOME' ENTERED AT 09:44:34 ON 12 SEP 2003

=> file inspec

| | | |
|----------------------|------------------|---------------|
| COST IN U.S. DOLLARS | SINCE FILE ENTRY | TOTAL SESSION |
| FULL ESTIMATED COST | 0.21 | 0.21 |

FILE 'INSPEC' ENTERED AT 09:44:53 ON 12 SEP 2003

Compiled and produced by the IEE in association with FIZ KARLSRUHE
COPYRIGHT 2003 (c) INSTITUTION OF ELECTRICAL ENGINEERS (IEE)

FILE LAST UPDATED: 8 SEP 2003 <20030908/UP>
FILE COVERS 1969 TO DATE.

<<< SIMULTANEOUS LEFT AND RIGHT TRUNCATION AVAILABLE IN
THE BASIC INDEX >>>

=> % memory

L1 124328 MEMORY

=> % nanotube

L2 3438 NANOTUBE

=> % l1 and l2

L3 21 L1 AND L2

=> & l3 1-21

L3 ANSWER 1 OF 21 INSPEC (C) 2003 IEE on STN

| | |
|-----------|------------|
| Full Text | References |
|-----------|------------|

AN 2003:7688442 INSPEC DN A2003-17-8120V-003; B2003-08-0587-018
TI Growth of isolated carbon nanotubes with lithographically defined diameter and location.
AU Duesberg, G.S.; Graham, A.P.; Liebau, M.; Seidel, R.; Unger, E.; Kreupl, F.; Hoenlein, W. (Infineon Technol. AG, Munich, Germany)
SO Nano Letters (Feb. 2003) vol.3, no.2, p.257-9. 17 refs.
Published by: American Chem. Soc
Price: CCCC 1530-6984/03/\$25.00
CODEN: NALEFD ISSN: 1530-6984
SICI: 1530-6984(200302)3:2L.257:GICN;1-7
DT Journal
TC Experimental
CY United States
LA English

L3 ANSWER 2 OF 21 INSPEC (C) 2003 IEE on STN

| | |
|-----------|------------|
| Full Text | References |
|-----------|------------|

AN 2003:7669655 INSPEC DN B2003-08-1265D-005
TI Concepts for hybrid CMOS-molecular non-volatile memories.
AU Luyken, R.J.; Hofmann, F. (Infineon Technol., Munchen, Germany)
SO Nanotechnology (Feb. 2003) vol.14, no.2, p.273-6. 15 refs.
Doc. No.: S0957-4484(03)53154-3
Published by: IOP Publishing
Price: CCCC 0957-4484/03/020273+04\$30.00

CODEN: NNOTER ISSN: 0957-4484
SICI: 0957-4484(200302)14:2L.273:CHCM;1-T
Conference: Trends in Nanotechnology (TNT 2002) Conference. Santiago de Compostela, Spain, 9-13 Sept 2002

DT Conference Article; Journal
TC General Review
CY United Kingdom
LA English

L3 ANSWER 3 OF 21 INSPEC (C) 2003 IEE on STN

| | |
|--------------|---------------------|
| Full Text | Cited References |
|--------------|---------------------|

AN 2003:7615271 INSPEC DN B2003-06-2230F-011
TI **Memory** effect and role of defects in carbon **nanotube** field effect transistors.
AU Johnson, A.T. (Dept. of Phys. & Astron., Pennsylvania Univ., Philadelphia, PA, USA)
SO AIP Conference Proceedings (2002) no.633, p.526-30. 19 refs.
Published by: AIP
Price: CCCC 0094-243X/2002/\$19.00
CODEN: APCPCS ISSN: 0094-243X
SICI: 0094-243X(2002)633L.526:MERD;1-D
DT Journal
TC Practical; Experimental
CY United States
LA English

L3 ANSWER 4 OF 21 INSPEC (C) 2003 IEE on STN

| | |
|--------------|---------------------|
| Full Text | Cited References |
|--------------|---------------------|

AN 2003:7582767 INSPEC DN A2003-10-0710C-002; B2003-05-2230F-005
TI A carbon- **nanotube**-based nanorelay.
AU Kinaret, J.M.; Nord, T.; Viefers, S. (Dept. of Appl. Phys., Chalmers Univ. of Technol., Goteborg, Sweden)
SO Applied Physics Letters (24 Feb. 2003) vol.82, no.8, p.1287-9. 21 refs.
Published by: AIP
Price: CCCC 01/03/6951/2003/82(8)/1287(3)/\$19.00
CODEN: APPLAB ISSN: 0003-6951
SICI: 0003-6951(20030224)82:8L.1287:CNBN;1-1
DT Journal
TC Theoretical
CY United States
LA English

L3 ANSWER 5 OF 21 INSPEC (C) 2003 IEE on STN

| | |
|--------------|---------------------|
| Full Text | Cited References |
|--------------|---------------------|

AN 2003:7555336 INSPEC DN B2003-04-2230F-004
TI Carbon- **nanotube**-based nonvolatile **memory** with oxide-nitride-oxide film and nanoscale channel.
AU Won Bong Choi; Soodoo Chae; Eunju Bae; Jo-Won Lee (M D Lab., Samsung Adv. Inst. of Technol., Suwon, South Korea); Byoung-Ho Cheong; Jae-Ryoung Kim; Ju-Jin Kim
SO Applied Physics Letters (13 Jan. 2003) vol.82, no.2, p.275-7. 13 refs.
Published by: AIP
Price: CCCC 01/03/6951/2003/82(2)/275(3)/\$19.00
CODEN: APPLAB ISSN: 0003-6951
SICI: 0003-6951(20030113)82:2L.275:CNBN;1-1
DT Journal
TC Practical; Experimental
CY United States
LA English

L3 ANSWER 6 OF 21 INSPEC (C) 2003 IEE on STN

| | |
|--------------|--------------------|
| Full Text | CNBR References |
|--------------|--------------------|

AN 2003:7507209 INSPEC DN B2003-02-1265D-039
 TI A carbon **nanotube**-based random access **memory**.
 AU Sun Jin-peng; Wang Tai-hong (Inst. of Phys., Acad. Sinica, Beijing, China)
 SO Micronanoelectronic Technology (2002) vol.39, no.10, p.8-26. 10 refs.
 Published by: Editorial Board of Micronanoelectronic Technol
 ISSN: 1671-4776
 SICI: 1671-4776(2002)39:10L:8:CNBR;1-K
 DT Journal
 TC Practical; Theoretical
 CY China
 LA Chinese

L3 ANSWER 7 OF 21 INSPEC (C) 2003 IEE on STN

| | |
|--------------|--------------------|
| Full Text | CNBR References |
|--------------|--------------------|

AN 2003:7481698 INSPEC DN B2003-02-2230F-001
 TI Carbon **nanotube memory** devices of high charge storage stability.
 AU Cui, J.B.; Sordan, R.; Burghard, M.; Kern, K. (Max-Planck-Inst. fuer Festkoerperforschung, Stuttgart, Germany)
 SO Applied Physics Letters (21 Oct. 2002) vol.81, no.17, p.3260-2. 20 refs.
 Doc. No.: S0003-6951(02)03042-5
 Published by: AIP
 Price: CCCC 01/03/6951/2002/81(17)/3260(3)/\$19.00
 CODEN: APPLAB ISSN: 0003-6951
 SICI: 0003-6951(20021021)81:17L:3260:CNMD;1-Q
 DT Journal
 TC Practical; Experimental
 CY United States
 LA English

L3 ANSWER 8 OF 21 INSPEC (C) 2003 IEE on STN

| | |
|--------------|--------------------|
| Full Text | CNBR References |
|--------------|--------------------|

AN 2002:7462853 INSPEC DN B2003-01-2230F-008
 TI Concept for a highly scalable nonvolatile **nanotube** based **memory**.
 AU Luyken, R.J.; Hofmann, F. (Corporate Res., Infineon Technol., Munchen, Germany)
 SO AIP Conference Proceedings (2001) no.591, p.581-4. 8 refs.
 Published by: AIP
 Price: CCCC 0094-243X/01/\$18.00
 CODEN: APCPCS ISSN: 0094-243X
 SICI: 0094-243X(2001)591L:581:CHSN;1-M
 Conference: Electronic Properties of Molecular Nanostructures: 15th International Winterschool/Euroconference. Kirchberg, Austria, 3-10 March 2001
 DT Conference Article; Journal
 TC Practical; Experimental
 CY United States
 LA English

L3 ANSWER 9 OF 21 INSPEC (C) 2003 IEE on STN

| | |
|--------------|--------------------|
| Full Text | CNBR References |
|--------------|--------------------|

AN 2002:7458851 INSPEC DN B2003-01-2230F-004
 TI Nonvolatile molecular **memory** elements based on ambipolar **nanotube** field effect transistors.
 AU Radosavljevic, M.; Freitag, M.; Thadani, K.V.; Johnson, A.T. (Dept. of Phys. & Astron., Pennsylvania Univ., USA)
 SO Nano Letters (July 2002) vol.2, no.7, p.761-4. 31 refs.
 Published by: American Chem. Soc
 Price: CCCC 1530-6984/02/\$22.00
 CODEN: NALEFD ISSN: 1530-6984

SICI: 1530-6984(200207)2:7L.761:NMME;1-T
 DT Journal
 TC Experimental
 CY United States
 LA English

L3 ANSWER 10 OF 21 INSPEC (C) 2003 IEE on STN

| | |
|--------------|----------------------|
| Full Text | Citing References |
|--------------|----------------------|

AN 2002:7458850 INSPEC DN B2003-01-2230F-003
 TI High-mobility **nanotube** transistor **memory**.
 AU Fuhrer, M.S.; Kim, B.M.; Durkop, T.; Brintlinger, T. (Dept. of Phys., Maryland Univ., College Park, MD, USA)
 SO Nano Letters (July 2002) vol.2, no.7, p.755-9. 21 refs.
 Published by: American Chem. Soc
 Price: CCCC 1530-6984/02/\$22.00
 CODEN: NALEFD ISSN: 1530-6984
 SICI: 1530-6984(200207)2:7L.755:HMNT;1-I

DT Journal
 TC Experimental
 CY United States
 LA English

L3 ANSWER 11 OF 21 INSPEC (C) 2003 IEE on STN

| | |
|--------------|----------------------|
| Full Text | Citing References |
|--------------|----------------------|

AN 2002:7448416 INSPEC DN B2002-12-2230F-006
 TI A carbon **nanotube**-based nonvolatile random access **memory**.
 AU Sun Jin-Peng; Wang Tai-Hong (Inst. of Phys., Acad. Sinica, Beijing, China)
 SO Acta Physica Sinica (2002) vol.51, no.9, p.2096-100. 7 refs.
 Published by: Chinese Phys. Soc
 CODEN: WLHPAR ISSN: 1000-3290
 SICI: 1000-3290(2002)51:9L.2096:CNBN;1-A

DT Journal
 TC Theoretical
 CY China
 LA Chinese

L3 ANSWER 12 OF 21 INSPEC (C) 2003 IEE on STN

| | |
|--------------|----------------------|
| Full Text | Citing References |
|--------------|----------------------|

AN 2002:7447571 INSPEC DN A2002-24-0710C-008; B2002-12-2575-019
 TI Pneumatic actuator response from carbon **nanotube** sheets.
 AU Spinks, G.M.; Wallace, G.G. (Intelligent Polymer Res. Inst., Wollongong Univ., NSW, Australia); Fifield, L.S.; Dalton, L.R.; Mazzoldi, A.; De Rossi, D.; Khayrullin, I.I.; Baughman, R.H.
 SO Making Functional Materials with Nanotubes. Symposium (Materials Research Society Symposium Proceedings Vol.706)
 Editor(s): Bernier, P.; Ajayan, P.; Iwasa, Y.; Nikolaev, P.
 Warrendale, PA, USA: Mater. Res. Soc, 2002. p.301-6 of xiii+388 pp. 9 refs.
 Conference: Boston, MA, USA, 26-29 Nov 2001
 ISBN: 1-55899-642-7

DT Conference Article
 TC Experimental; Practical
 CY United States
 LA English

L3 ANSWER 13 OF 21 INSPEC (C) 2003 IEE on STN

| | |
|--------------|----------------------|
| Full Text | Citing References |
|--------------|----------------------|

AN 2002:7439296 INSPEC DN B2002-12-2230-008
 TI Molecular-scale engineering for future electronics.
 AU Tsui, R.

SO 2002 IEEE International Symposium on Circuits and Systems. Proceedings
(Cat. No.02CH37353)
Piscataway, NJ, USA: IEEE, 2002. p.II-41 vol.2 of 5
vol.(cxxi+924+886+898+889+871) pp.
Conference: Phoenix-Scottsdale, AZ, USA, 26-29 May 2002
Sponsor(s): IEEE; IEEE Circuits & Syst. Soc
Price: CCCC 0-7803-7448-7/02/\$17.00
ISBN: 0-7803-7448-7
DT Conference Article
TC General Review
CY United States
LA English

L3 ANSWER 14 OF 21 INSPEC (C) 2003 IEE on STN

| | |
|--------------|------------|
| Full Text | References |
|--------------|------------|

AN 2002:7407347 INSPEC DN A2002-22-8120V-016; B2002-11-0587-020
TI Applications of carbon nanotubes to electron emitters.
AU Young Hee Lee; Seong Chu Lim; Kay Hyeok An; Won Seok Kim; Hee Jin Jeong;
Young Min Shin (Nat. Res. Lab. for Carbon Nanotubes, Sung Kyun Kwan Univ.,
Suwon, South Korea); Hwi-Gun Lee; Jong Min Kim
SO New Diamond and Frontier Carbon Technology (2002) vol.12, no.4, p.181-207.
51 refs.
Published by: MYU
CODEN: NDFTFF ISSN: 1344-9931
SICI: 1344-9931(2002)12:4L:181:ACNE;1-K
Conference: 6th Applied Diamond Conference/2nd Frontier Carbon Technology
Joint Conference. Auburn, AL, USA, Aug 2001
DT Conference Article; Journal
TC Application; Bibliography; Experimental
CY Japan
LA English

L3 ANSWER 15 OF 21 INSPEC (C) 2003 IEE on STN

| | |
|--------------|------------|
| Full Text | References |
|--------------|------------|

AN 2002:7380161 INSPEC DN B2002-10-2230F-013
TI Charge transfer control by gate voltage in crossed **nanotube** junction.
AU Yoneya, N. (RIKEN, Saitama, Japan); Tsukagoshi, K.; Aoyagi, Y.
SO Applied Physics Letters (16 Sept. 2002) vol.81, no.12, p.2250-2. 15 refs.
Doc. No.: S0003-6951(02)04437-6
Published by: AIP
Price: CCCC 0003-6951/2002/81(12)/2250(3)/\$19.00
CODEN: APPLAB ISSN: 0003-6951
SICI: 0003-6951(20020916)81:12L:2250:CTCG;1-O
DT Journal
TC Experimental
CY United States
LA English

L3 ANSWER 16 OF 21 INSPEC (C) 2003 IEE on STN

| | |
|--------------|------------|
| Full Text | References |
|--------------|------------|

AN 2002:7340656 INSPEC DN B2002-09-2550N-012
TI Nanotechnology goals and challenges for electronic applications.
AU Bohr, M.T. (Intel Corp., Hillsboro, OR, USA)
SO IEEE Transactions on Nanotechnology (March 2002) vol.1, no.1, p.56-62. 62
refs.
Doc. No.: S1536-125X(02)04586-6
Published by: IEEE
Price: CCCC 1536-125X/02/\$17.00
CODEN: ITNECU ISSN: 1536-125X
SICI: 1536-125X(200203)1:1L:56:NGCE;1-J
DT Journal

TC Application; Bibliography; General Review
CY United States
LA English

L3 ANSWER 17 OF 21 INSPEC (C) 2003 IEE on STN

| | |
|--------------|---------------------|
| Full Text | Cited References |
|--------------|---------------------|

AN 2002:7252241 INSPEC DN A2002-11-7125X-006; B2002-06-0587-002
TI Bandgap modulation of carbon nanotubes by encapsulated metallofullerenes.
AU Jhinwan Lee; Kim, H. (Sch. of Phys., Seoul Nat. Univ., South Korea);
Kahng, S.-J.; Kim, G.; Son, Y.-W.; Ihm, J.; Kato, H.; Wang, Z.W.; Okazaki,
T.; Shinohara, H.; Young Kuk, Y.
SO Nature (28 Feb. 2002) vol.415, no.6875, p.1005-8. 23 refs.
Published by: Nature Publishing Group
Price: CCCC 0028-0836/02/\$12.00+2.00
CODEN: NATUAS ISSN: 0028-0836
SICI: 0028-0836(20020228)415:6875L.1005:BMCN;1-H
DT Journal
TC Experimental
CY United Kingdom
LA English

L3 ANSWER 18 OF 21 INSPEC (C) 2003 IEE on STN

| | |
|--------------|---------------------|
| Full Text | Cited References |
|--------------|---------------------|

AN 2002:7136481 INSPEC DN B2002-02-1265B-015
TI Logic circuits with carbon **nanotube** transistors.
AU Bachtold, A.; Hadley, P.; Nakanishi, T.; Dekker, C. (Dept. of Appl. Phys.,
Delft Univ. of Technol., Netherlands)
SO Science (9 Nov. 2001) vol.294, no.5545, p.1317-20. 37 refs.
Published by: American Assoc. Adv. Sci
Price: CCCC 0036-8075/01/\$8.00
CODEN: SCIEAS ISSN: 0036-8075
SICI: 0036-8075(20011109)294:5545L.1317:LCWC;1-G
DT Journal
TC Practical; Experimental
CY United States
LA English

L3 ANSWER 19 OF 21 INSPEC (C) 2003 IEE on STN

| | |
|--------------|---------------------|
| Full Text | Cited References |
|--------------|---------------------|

AN 2001:6937088 INSPEC DN A2001-13-4265-005
TI Observation of self-diffraction by gratings in nematic liquid crystals
doped with carbon nanotubes.
AU Wei Lee; Chi-Shen Chiu (Dept. of Phys., Chung Yuan Christian Univ., Chung
Li, Taiwan)
SO Optics Letters (15 April 2001) vol.26, no.8, p.521-3. 24 refs.
Published by: Opt. Soc. America
CODEN: OPLEDP ISSN: 0146-9592
SICI: 0146-9592(20010415)26:8L.521:OSDG;1-8
DT Journal
TC Theoretical; Experimental
CY United States
LA English

L3 ANSWER 20 OF 21 INSPEC (C) 2003 IEE on STN

| | |
|--------------|---------------------|
| Full Text | Cited References |
|--------------|---------------------|

AN 2000:6702451 INSPEC DN B2000-10-2230F-003; C2000-10-5320Z-001
TI Carbon **nanotube**-based nonvolatile random access **memory** for molecular
computing.
AU Rueckes, T. (Dept. of Chem., Harvard Univ., Cambridge, MA, USA); Kim, K.;
Joselevich, E.; Tseng, G.Y.; Cheung, C.-L.; Lieber, C.M.

SO Science (7 July 2000) vol.289, no.5476, p.94-7. 30 refs.
 Published by: American Assoc. Adv. Sci
 Price: CCCC 0036-8075/2000/\$8.00
 CODEN: SCIEAS ISSN: 0036-8075
 SICI: 0036-8075(20000707)289:5476L.94:CNBN;1-G
 DT Journal
 TC Theoretical; Experimental
 CY United States
 LA English

L3 ANSWER 21 OF 21 INSPEC (C) 2003 IEE on STN



AN 2000:6504820 INSPEC DN B2000-03-2230F-007
 TI The potential of carbon-based **memory** systems.
 AU Brehob, M.; Enbody, R.; Young-Kyun Kwon; Tomanek, D. (Dept. of Comput.
 Sci. & Eng., Michigan State Univ., East Lansing, MI, USA)
 SO Records of the 1999 IEEE International Workshop on Memory Technology,
 Design and Testing
 Editor(s): Rajsuman, R.; Wik, T.
 Los Alamitos, CA, USA: IEEE Comput. Soc, 1999. p.110-14 of ix+131 pp. 7
 refs.
 Conference: San Jose, CA, USA, 9-10 Aug 1999
 Sponsor(s): IEEE Comput. Soc.; IEEE Comput. Soc. Tech. Committee on VLSI;
 IEEE Comput. Soc. Techno. Council on Test Technol
 Price: CCCC 0 7695 0259 8/99/\$10.00
 ISBN: 0-7695-0259-8
 DT Conference Article
 TC General Review; Theoretical
 CY United States
 LA English

=>